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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
09/832,892	04/12/2001	Takehisa Yamaguchi	20597US2	1675
22850	7590	11/06/2006	EXAMINER	
C. IRVIN MCCLELLAND OBLON, SPIVAK, MCCLELLAND, MAIER & NEUSTADT, P.C. 1940 DUKE STREET ALEXANDRIA, VA 22314			NGUYEN, HOAN C	
		ART UNIT	PAPER NUMBER	
			2871	

DATE MAILED: 11/06/2006

Please find below and/or attached an Office communication concerning this application or proceeding.

Office Action Summary	Application No.	Applicant(s)
	09/832,892	YAMAGUCHI ET AL.
	Examiner	Art Unit
	HOAN C. NGUYEN	2871

-- The MAILING DATE of this communication appears on the cover sheet with the correspondence address --

Period for Reply

A SHORTENED STATUTORY PERIOD FOR REPLY IS SET TO EXPIRE 3 MONTH(S) OR THIRTY (30) DAYS, WHICHEVER IS LONGER, FROM THE MAILING DATE OF THIS COMMUNICATION.

- Extensions of time may be available under the provisions of 37 CFR 1.136(a). In no event, however, may a reply be timely filed after SIX (6) MONTHS from the mailing date of this communication.
- If NO period for reply is specified above, the maximum statutory period will apply and will expire SIX (6) MONTHS from the mailing date of this communication.
- Failure to reply within the set or extended period for reply will, by statute, cause the application to become ABANDONED (35 U.S.C. § 133). Any reply received by the Office later than three months after the mailing date of this communication, even if timely filed, may reduce any earned patent term adjustment. See 37 CFR 1.704(b).

Status

1) Responsive to communication(s) filed on 22 September 2006.

2a) This action is **FINAL**. 2b) This action is non-final.

3) Since this application is in condition for allowance except for formal matters, prosecution as to the merits is closed in accordance with the practice under *Ex parte Quayle*, 1935 C.D. 11, 453 O.G. 213.

Disposition of Claims

4) Claim(s) 1-13 is/are pending in the application.
4a) Of the above claim(s) 6-13 is/are withdrawn from consideration.
5) Claim(s) _____ is/are allowed.
6) Claim(s) 1-5 is/are rejected.
7) Claim(s) _____ is/are objected to.
8) Claim(s) _____ are subject to restriction and/or election requirement.

Application Papers

9) The specification is objected to by the Examiner.

10) The drawing(s) filed on _____ is/are: a) accepted or b) objected to by the Examiner.

Applicant may not request that any objection to the drawing(s) be held in abeyance. See 37 CFR 1.85(a).

Replacement drawing sheet(s) including the correction is required if the drawing(s) is objected to. See 37 CFR 1.121(d).

11) The oath or declaration is objected to by the Examiner. Note the attached Office Action or form PTO-152.

Priority under 35 U.S.C. § 119

12) Acknowledgment is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d) or (f).
a) All b) Some * c) None of:
1. Certified copies of the priority documents have been received.
2. Certified copies of the priority documents have been received in Application No. _____.
3. Copies of the certified copies of the priority documents have been received in this National Stage application from the International Bureau (PCT Rule 17.2(a)).

* See the attached detailed Office action for a list of the certified copies not received.

Attachment(s)

1) Notice of References Cited (PTO-892) 4) Interview Summary (PTO-413)
2) Notice of Draftsperson's Patent Drawing Review (PTO-948) Paper No(s)/Mail Date. ____ .
3) Information Disclosure Statement(s) (PTO/SB/08)
Paper No(s)/Mail Date 9/21/06. 5) Notice of Informal Patent Application
6) Other: ____ .

DETAILED ACTION

Continued Examination Under 37 CFR 1.114

A request for continued examination under 37 CFR 1.114, including the fee set forth in 37 CFR 1.17(e), was filed in this application after allowance or after an Office action under *Ex Parte Quayle*, 25 USPQ 74, 453 O.G. 213 (Comm'r Pat. 1935). Since this application is eligible for continued examination under 37 CFR 1.114, and the fee set forth in 37 CFR 1.17(e) has been timely paid, prosecution in this application has been reopened pursuant to 37 CFR 1.114. Applicant's submission filed on 9/21/2006 has been entered.

On 09/21/2006, applicants withdraw from issue for submitting the translation of a part of Korean Patent Publication No. 0079893/1999, in which the names of drain electrode and source electrode have been reversed (source electrode being drain electrode and drain electrode being source electrode).

Due to new prior 0079893/1999 submitted by applicants, the allowance mailed on 5/12/2004 is withdrawn.

This rejection is based on the response for after final filed on 09/02/2003. Therefore, the only claims 1-5 are considered, the non-elected claims 6-13 are withdrawn as before.

Claim Rejections - 35 USC § 103

The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:

(a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negated by the manner in which the invention was made.

1. Claims 1-5 are rejected under 35 U.S.C. 103(a) as being unpatentable over Takashi (JP1267617) in view of prior art of 0079893/1999 submitted by application in IDS.

Takaki teaches (Fig. 1) a liquid crystal display comprising:

- a gate electrode line 106 including a gate electrode formed on an insulating substrate;
- a source electrode line 108 including a source electrode 103 intersected with said gate electrode line 106 via an insulating film (gate insulating film 105);
- a thin film transistor including said gate electrode, said source electrode, and two drain electrodes located in a vicinity of a portion in which said gate electrode line is intersected with said source electrode line;
- two drain electrode lines 102, each including a portion acting as one of the two drain electrodes, said two drain electrode lines being connected with a pixel electrode 107;

wherein

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- said two drain electrodes are located on opposite sides of said source electrode with each of said two drain electrodes having a near side opposed to said source electrode that is superposed with said gate electrode and a far side opposed to near side that is not superposed with said gate electrode.

Claim 2:

- an area of a region where said gate electrode line 106 is superposed with the near side of one of said two drain electrodes is substantially identical to an area of a region where said gate electrode is superposed with the other one of said two drain electrodes as shown in Fig. 1b.

Claim 3:

- a length of a region in a channel lengthwise direction of said thin film transistor where said gate electrode is superposed with the near side of one of said two drain electrodes is substantially identical to a length 109 of a region in a channel lengthwise direction of said thin film transistor where said gate electrode line is superposed with the near side of other one of said two drain electrodes;

Claim 5:

- said two drain electrodes are formed in whole part of one end of said drain electrode line in a channel widthwise direction where the near side of each drain electrode is superposed with said gate electrode line;

However, Takashi (JP1267617) fails to disclose each of two drain electrodes having (a) a near side facing in parallel with source electrode; and being superposed

with the gate electrode; a far side opposed to and in parallel with the near side; and not being superposed with the gate electrode with the property stated in claim 4.

Prior art of 0079893/1999 teaches each of two drain electrodes having a near side facing in parallel with source electrode; and being superposed with the gate electrode; a far side opposed to and in parallel with the near side; and not being superposed with the gate electrode for minimizing of deviation of kickback voltage, thus. said length of the region in the channel lengthwise direction is such a length for preventing current characteristics from degradation in a thin film transistor.

Therefore, it would have been obvious to one having ordinary skill in the art at the time the invention was made to further modify a liquid crystal display device as Takashi disclosed with each of two drain electrodes having a near side facing in parallel with source electrode; and being superposed with the gate electrode; a far side opposed to and in parallel with the near side; and not being superposed with the gate electrode for minimizing of deviation of kickback voltage as taught by prior art of 0079893/1999, thus. said length of the region in the channel lengthwise direction is such a length for preventing current characteristics from degradation in a thin film transistor.

Conclusion

Any inquiry concerning this communication or earlier communications from the examiner should be directed to HOAN C. NGUYEN whose telephone number is (571)

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272-2296. The examiner can normally be reached on MONDAY-THURSDAY:8:00AM-4:30PM.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, David Nelms can be reached on (571) 272-1787. The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see <http://pair-direct.uspto.gov>. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free). If you would like assistance from a USPTO Customer Service Representative or access to the automated information system, call 800-786-9199 (IN USA OR CANADA) or 571-272-1000.

HOAN C. NGUYEN
Examiner
Art Unit 2871

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Andrew Schechter
ANDREW SCHECHTER
PRIMARY EXAMINER